S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	Applicant(s)/Patent under Reexamination	
10/728,517	KIM ET AL.		
Examiner	Art Unit		
Toniae M. Thomas	2822		

	SEAR	CHED	
Class	Subclass	Date	Examiner
438	586, 649, 656, 664, 683, 755	9/23/2005	ТМТ
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB (see search history printout)	9/23/2005	ТМТ
US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB (see search history printout)	10/1/2005	ТМТ